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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/622,982	CHAN ET AL.	
Examiner	Art Unit	

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Liang-che Alex Wang

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Class	Subclass	Date	Examiner	
709	205-207	2/1/2007	LW	
715	752	2/1/2007	LW	
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Updated EAST search: USPAT, USPUB, EPO, JPO, DERWENT	2/1/2007	LW	
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